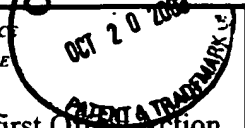


FORM PTO-1449	US DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		Atty. Docket No. <b>83559RLW</b> Customer No. 01333	Serial No. <b>10/625,426</b>
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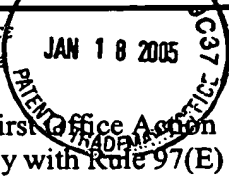
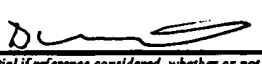
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